MOTOROLA
SEMICONDUCTOR
TECHNICAL DATA

MTM2N50

Designer's Data Sheet

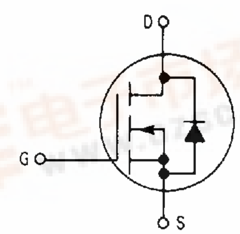
Power Field Effect Transistor

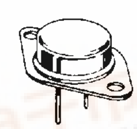
N-Channel Enhancement-Mode Silicon Gate

TMOS POWER FET
2 AMPERES
$R_{DS(on)}$ = 4 OHMS
500 VOLTS

This TMOS Power FET is designed for high voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

- Silicon Gate for Fast Switching Speeds — Switching Times Specified at 100°C
- Designer's Data — I_{DSS}, $V_{DS(on)}$, $V_{GS(th)}$ and SOA Specified at Elevated Temperature
- Rugged — SOA is Power Dissipation Limited
- Source-to-Drain Diode Characterized for Use With Inductive Loads





CASE 1-07
TO-204AA

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	500	Vdc
Drain-Gate Voltage (R_{GS} = 1 MΩ)	V_{DGR}	500	Vdc
Gate-Source Voltage — Continuous — Non-repetitive ($t_p \leq 50\ \mu s$)	V_{GS} V_{GSM}	±20 ±40	Vdc Vpk
Drain Current Continuous Pulsed	 I_D I_{DM}	 2 7	Adc
Total Power Dissipation @ T_C = 25°C Derate above 25°C	P_D	75 0.6	Watts W/°C
Operating and Storage Temperature Range	T_J, T_{stg}	−65 to 150	°C

THERMAL CHARACTERISTICS

Thermal Resistance Junction to Case Junction to Ambient	 $R_{\theta JC}$ $R_{\theta JA}$	 1.67 30	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8″ from case for 5 seconds	T_L	300	°C

Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design.

3

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Max	Unit
OFF CHARACTERISTICS					
Drain-Source Breakdown Voltage (V_{GS} = 0, I_D = 0.25 mA)	MTP2N45 MTM/MTP2N50	$V_{(BR)DSS}$	450 500	— —	Vdc
Zero Gate Voltage Drain Current (V_{DS} = Rated V_{DSS}, V_{GS} = 0) (V_{DS} = 0.8 Rated V_{DSS}, V_{GS} = 0, T_J = 125°C)		I_{DSS}	— —	0.2 1	mAdc
Gate-Body Leakage Current, Forward (V_{GSF} = 20 Vdc, V_{DS} = 0)		I_{GSSF}	—	100	nAdc
Gate-Body Leakage Current, Reverse (V_{GSR} = 20 Vdc, V_{DS} = 0)		I_{GSSR}	—	100	nAdc
ON CHARACTERISTICS*					
Gate Threshold Voltage (V_{DS} = V_{GS}, I_D = 1 mA) T_J = 100°C		$V_{GS(th)}$	2 1.5	4.5 4	Vdc
Static Drain-Source On-Resistance (V_{GS} = 10 Vdc, I_D = 1 Adc)		$R_{DS(on)}$	—	4	Ohms
Drain-Source On-Voltage (V_{GS} = 10 V) (I_D = 2 Adc) (I_D = 1 Adc, T_J = 100°C)		$V_{DS(on)}$	— —	10 8	Vdc
Forward Transconductance (V_{DS} = 15 V, I_D = 1 A)		g_{FS}	1	—	mhos
DYNAMIC CHARACTERISTICS					
Input Capacitance	(V_{DS} = 25 V, V_{GS} = 0, f = 1 MHz) See Figure 11	C_{iss}	—	500	pF
Output Capacitance		C_{oss}	—	100	
Reverse Transfer Capacitance		C_{rss}	—	50	
SWITCHING CHARACTERISTICS* (T_J = 100°C)					
Turn-On Delay Time	(V_{DD} = 25 V, I_D = 0.5 Rated I_D R_{gen} = 50 ohms) See Figures 9, 13 and 14	$t_{d(on)}$	—	40	ns
Rise Time		t_r	—	60	
Turn-Off Delay Time		$t_{d(off)}$	—	60	
Fall Time		t_f	—	30	
Total Gate Charge	(V_{DS} = 0.8 Rated V_{DSS}, I_D = Rated I_D, V_{GS} = 10 V) See Figure 12	Q_g	17 (Typ)	25	nC
Gate-Source Charge		Q_{gs}	9 (Typ)	—	
Gate-Drain Charge		Q_{gd}	8 (Typ)	—	
SOURCE DRAIN DIODE CHARACTERISTICS*					
Forward On-Voltage	(I_S = Rated I_D V_{GS} = 0)	V_{SD}	1 (Typ)	1.5	Vdc
Forward Turn-On Time		t_{on}	Limited by stray inductance		
Reverse Recovery Time		t_{rr}	200 (Typ)	—	ns
INTERNAL PACKAGE INDUCTANCE (TO-204)					
Internal Drain Inductance (Measured from the contact screw on the header closer to the source pin and the center of the die)		L_d	5 (Typ)	—	nH
Internal Source Inductance (Measured from the source pin, 0.25″ from the package to the source bond pad)		L_s	12.5 (Typ)	—	

*Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%

TYPICAL ELECTRICAL CHARACTERISTICS

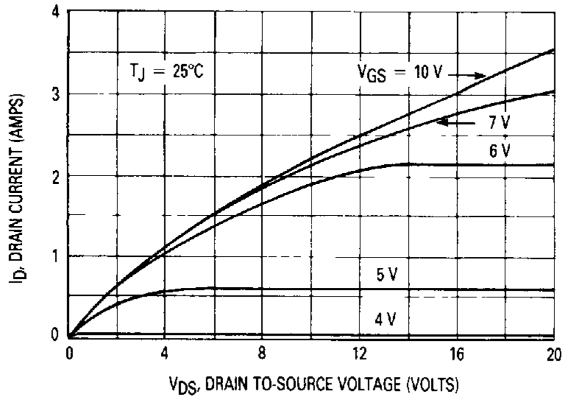


Figure 1. On-Region Characteristics

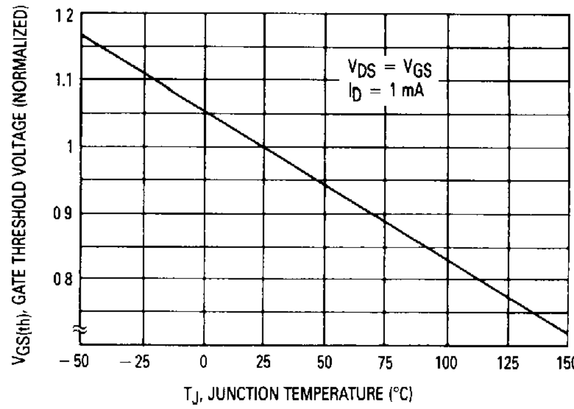


Figure 2. Gate-Threshold Voltage Variation With Temperature

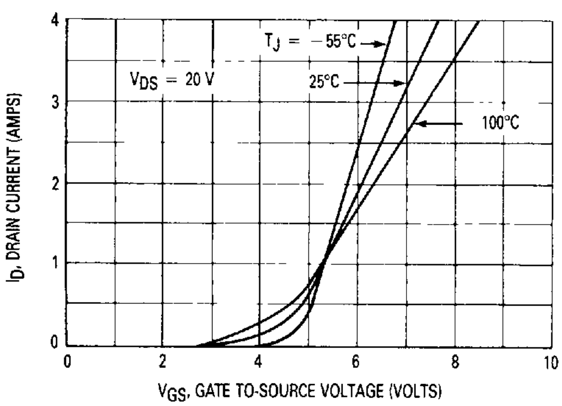


Figure 3. Transfer Characteristics

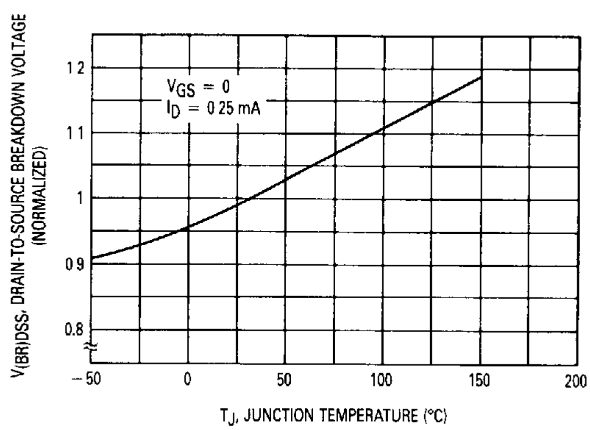


Figure 4. Breakdown Voltage Variation With Temperature

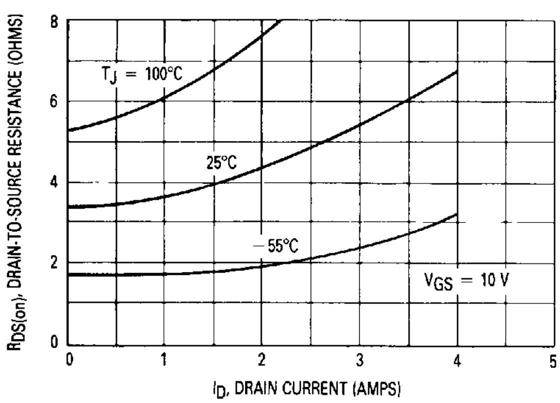


Figure 5. On-Resistance versus Drain Current

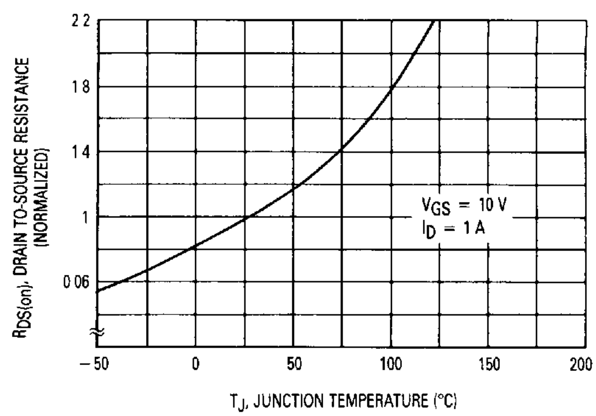


Figure 6. On-Resistance Variation With Temperature

SAFE OPERATING AREA INFORMATION

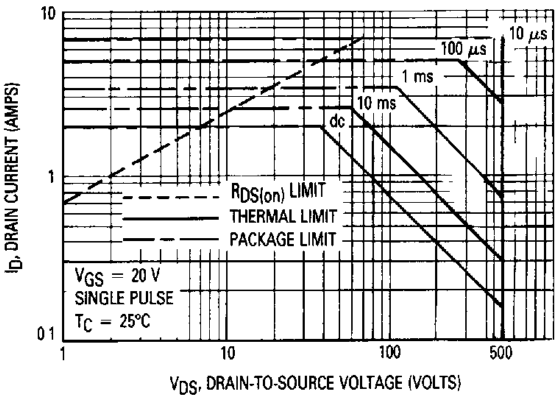


Figure 7. Maximum Rated Forward Biased Safe Operating Area

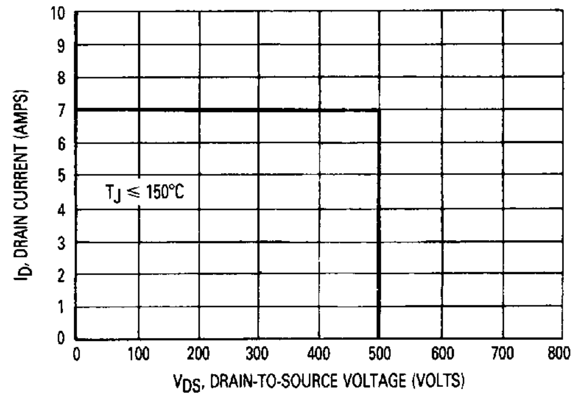


Figure 8. Maximum Rated Switching Safe Operating Area

FORWARD BIASED SAFE OPERATING AREA

The FBSOA curves define the maximum drain-to-source voltage and drain current that a device can safely handle when it is forward biased, or when it is on, or being turned on. Because these curves include the limitations of simultaneous high voltage and high current, up to the rating of the device, they are especially useful to designers of linear systems. The curves are based on a case temperature of 25°C and a maximum junction temperature of 150°C. Limitations for repetitive pulses at various case temperatures can be determined by using the thermal response curves. Motorola Application Note, AN569, "Transient Thermal Resistance-General Data and Its Use" provides detailed instructions.

SWITCHING SAFE OPERATING AREA

The switching safe operating area (SOA) of Figure 8 is the boundary that the load line may traverse without incurring damage to the MOSFET. The fundamental limits are the peak current, I_{DM} and the breakdown voltage, $V_{(BR)DSS}$. The switching SOA shown in Figure 8 is applicable for both turn-on and turn-off of the devices for switching times less than one microsecond.

The power averaged over a complete switching cycle must be less than:

$$\frac{T_{J(max)} - T_C}{R_{\theta JC}}$$

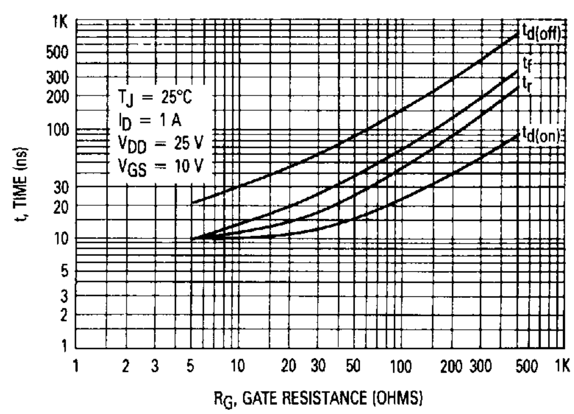


Figure 9. Resistive Switching Time Variation versus Gate Resistance

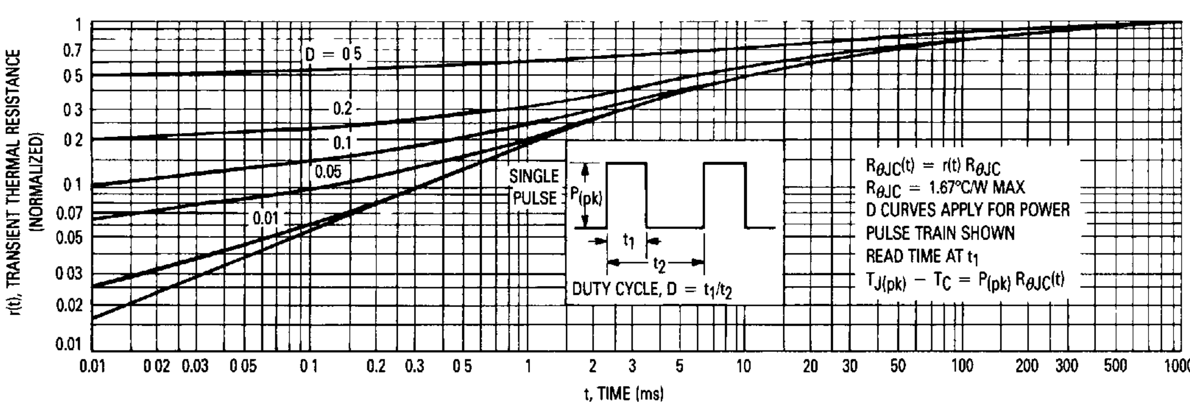


Figure 10. Thermal Response

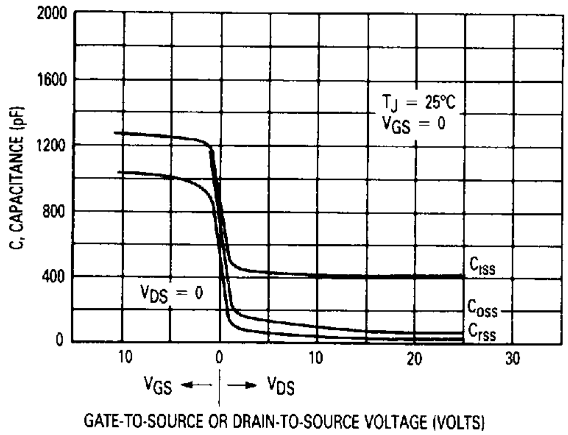


Figure 11. Capacitance Variation

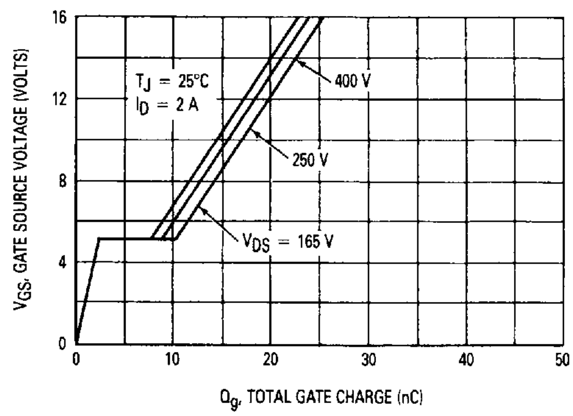


Figure 12. Gate Charge versus Gate-to-Source Voltage

3

RESISTIVE SWITCHING

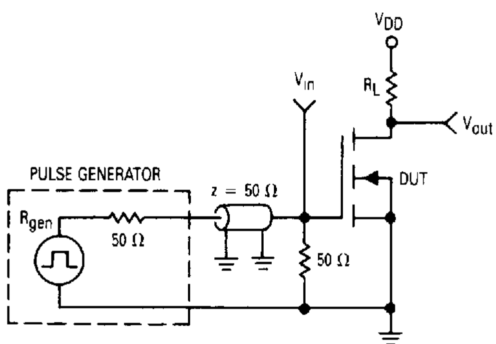


Figure 13. Switching Test Circuit

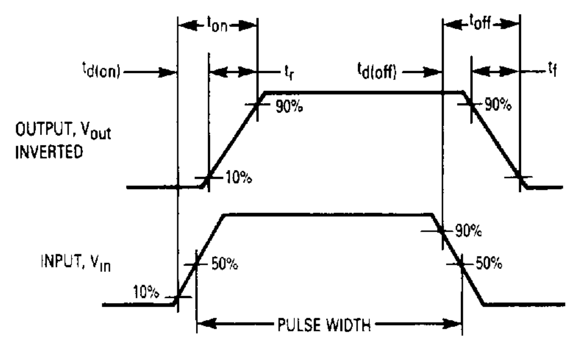


Figure 14. Switching Waveforms